

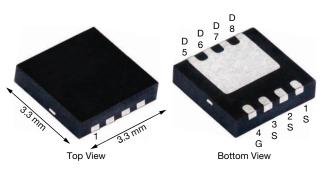
RoHS

COMPLIANT HALOGEN

BSZ520N15NS3 G-VB Datasheet N-Channel 150 V (D-S) MOSFET

PRODUCT SUMMARY	
V _{DS} (V)	150
$R_{DS(on)}$ (Ω) at V_{GS} = 10 V	0.035
Q _g typ. (nC)	8.5
I _D (A)	25.5 ^a
Configuration	Single

DFN 3x3 EP

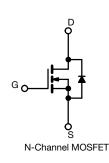


FEATURES

- Trench Cell optimizes balance of R_{DS(on)}, Q_g, Q_{sw}, and Q_{oss}
- 100 % R_g and UIS tested

APPLICATIONS

- Primary side switching
- Synchronous rectification
- DC/DC converter
- Motor drive control
- Load switch



ABSOLUTE MAXIMUM RATING	3S (Τ _A = 25 °C, ι	Inless otherv	vise noted)	
PARAMETER		SYMBOL	LIMIT	UNIT
Drain-source voltage		V _{DS}	150	V
Gate-source voltage		V _{GS}	± 20	v
Continuous drain current (T _J = 150 °C)	T _C = 25 °C		25.5	
	T _C = 70 °C		20.4	
	T _A = 25 °C	I _D	7 ^{b, c}	
	T _A = 70 °C	1	5.6 ^{b, c}	•
Pulsed drain current (t = 100 µs)		I _{DM}	50	— A
Continuous source-drain diode current	T _C = 25 °C	- I _S	54.8	
	T _A = 25 °C		4.2 ^{b, c}	
Single pulse avalanche current		I _{AS}	20	
Single pulse avalanche energy	L = 0.1 mH	E _{AS}	20	mJ
Maximum power dissipation	T _C = 25 °C		65.8	
	T _C = 70 °C		42.1	14/
	T _A = 25 °C	PD	5.1 ^{b, c}	W
	T _A = 70 °C		3.2 ^{b, c}	
Operating junction and storage temperature range		T _J , T _{stg}	-55 to +150	*0
Soldering recommendations (peak temperature) ^c		1	260	

THERMAL RESISTANCE RATINGS

PARAMETER		SYMBOL	TYPICAL	MAXIMUM	UNIT	
Maximum junction-to-ambient ^b	t ≤ 10 s	R _{thJA}	20	25	°C/W	
Maximum junction-to-case (drain)	Steady state	R _{thJC}	1.5	1.9	- 0/10	

Notes

- a. T_C = 25 °C
- b. Surface mounted on 1" x 1" FR4 board

c. t = 10 s

- d. The DFN3x3 package is a leadless package. The end of the lead terminal is exposed copper (not plated) as a result of the singulation process in manufacturing. A solder fillet at the exposed copper tip cannot be guaranteed and is not required to ensure adequate bottom side solder interconnection
- e. Rework conditions: manual soldering with a soldering iron is not recommended for leadless components

f. Maximum under steady state conditions is 65 °C/W

PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT	
Static	L						
Drain-source breakdown voltage	V _{DS}	$V_{GS} = 0 V, I_D = 250 \mu A$	150	-	-	V	
V _{DS} temperature coefficient	$\Delta V_{DS}/T_{J}$	I _D = 250 mA	-	92	-		
V _{GS(th)} temperature coefficient	$\Delta V_{GS(th)}/T_J$	I _D = 250 μA	-	-7.1	-	mV/°C	
Gate-source threshold voltage	V _{GS(th)}	$V_{DS} = V_{GS}$, $I_D = 250 \ \mu A$	2	-	4	V	
Gate-source leakage	I _{GSS}	$V_{DS} = 0 V, V_{GS} = \pm 20 V$	-	-	100	nA	
Zero gate voltage drain current	I _{DSS} -	$V_{DS} = 150 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$	-	-	1	μA	
		V_{DS} = 150 V, V_{GS} = 0 V, T_{J} = 70 °C	-	-	15		
On-state drain current ^a	I _{D(on)}	$V_{DS} \le 10$ V, $V_{GS} = 10$ V	20	-	-	А	
Drain-source on-state resistance ^a	R _{DS(on)}	V _{GS} = 10 V, I _D = 7 A	-	0.035	-	Ω	
Forward transconductance a	9 _{fs}	V _{DS} = 15 V, I _D = 7 A	-	16	-	S	
Dynamic ^b	L						
Input capacitance	C _{iss}	V _{DS} = 75 V, V _{GS} = 0 V, f = 1 MHz	-	550	-	pF	
Output capacitance	C _{oss}		-	120	-		
Reverse transfer capacitance	C _{rss}		-	6	-		
-	<u> </u>	$V_{DS} = 75 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 7 \text{ A}$ $V_{DS} = 75 \text{ V}, V_{GS} = 7.5 \text{ V}, I_D = 7 \text{ A}$	-	10.85	22	nC	
Total gate charge	Qg		-	8.5	13		
Gate-source charge	Q _{gs}		-	3	-		
Gate-drain charge	Q _{gd}		-	3	-		
Output charge	Q _{oss}	$V_{DS} = 75 \text{ V}, V_{GS} = 0 \text{ V}$	-	27.7	42		
Gate resistance	R _g	f = 1 MHz	0.24	1.2	2.4	Ω	
Turn-on delay time	t _{d(on)}		-	18	36	-	
Rise time	t _r	$\label{eq:VDD} \begin{array}{l} V_{DD} = 75 \; V, R_L = 13.4 \; \Omega, I_D \cong 5.6 \; A, \\ V_{GEN} = 10 \; V, R_g = 1 \; \Omega \end{array}$	-	6	12		
Turn-off delay time	t _{d(off)}		-	30	60		
Fall time	t _f		-	9	18	1	
Turn-on delay time	t _{d(on)}		-	20	40	ns	
Rise time	t _r	$V_{DD} = 75 \text{ V}, \text{ R}_{L} = 13.4 \Omega, \text{ I}_{D} \cong 5.6 \text{ A},$	-	8	16	-	
Turn-off delay time	t _{d(off)}	V_{GEN} = 7.5 V, R _g = 1 Ω	-	25	50		
Fall time	t _f		-	11	22		
Drain-Source Body Diode Characteristic	cs						
Continuous source-drain diode current	Is	T _C = 25 °C	-	-	54.8	^	
Pulse diode forward current	I _{SM}	-		-	50	A	
Body diode voltage	V _{SD}	$I_{\rm S} = 5.6$ A, $V_{\rm GS} = 0$ V	-	0.8	1.2	V	
Body diode reverse recovery time	t _{rr}		-	60	120	ns	
Body diode reverse recovery charge	Q _{rr}	I _F = 5.6 A, di/dt = 100 A/μs,	-	133	266	nC	
Reverse recovery fall time	ta	$T_J = 25 \ ^{\circ}C$	-	50	-	- ns	
Reverse recovery rise time	t _b			10	_		

Notes

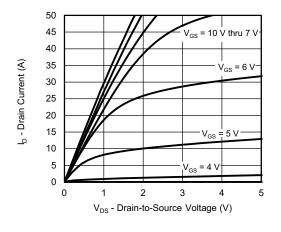
a. Pulse test; pulse width \leq 300 $\mu s,$ duty cycle \leq 2 %

b. Guaranteed by design, not subject to production testing

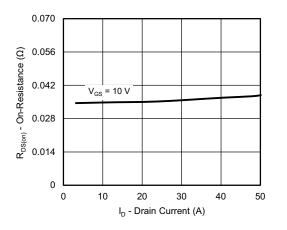
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

emi

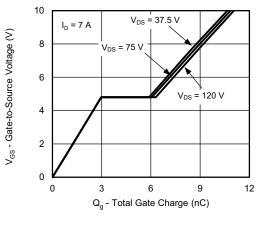




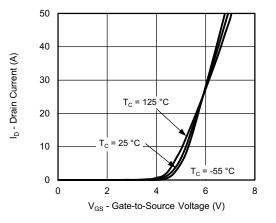
Output Characteristics



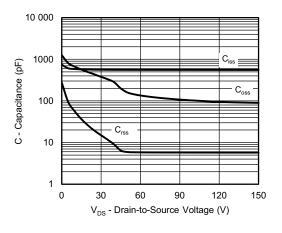
On-Resistance vs. Drain Current and Gate Voltage



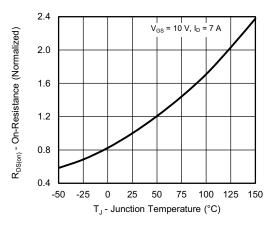
Gate Charge



Transfer Characteristics

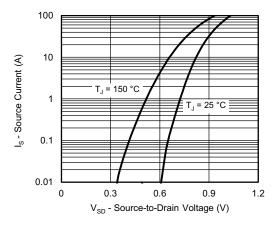


Capacitance

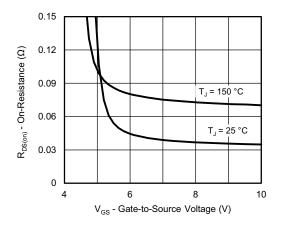


On-Resistance vs. Junction Temperature

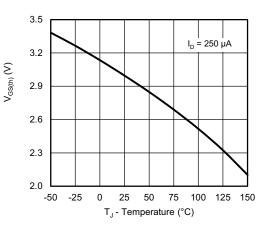




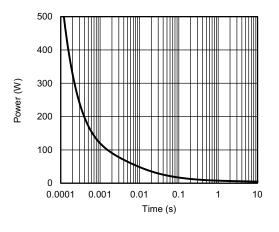
Source-Drain Diode Forward Voltage



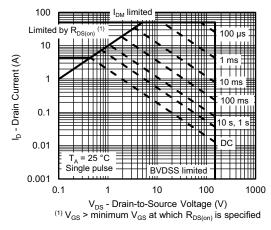
On-Resistance vs. Gate-to-Source Voltage



Threshold Voltage

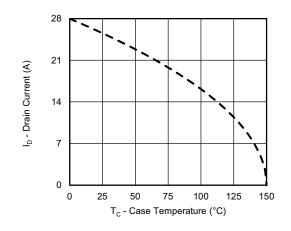


Single Pulse Power, Junction-to-Ambient

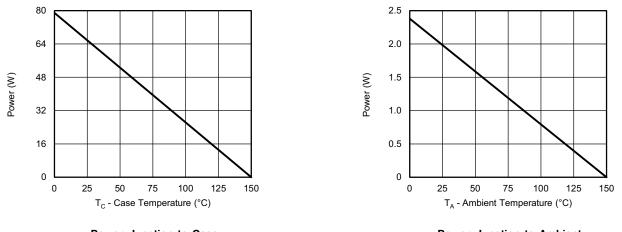


Safe Operating Area, Junction-to-Ambient





Current Derating ^a



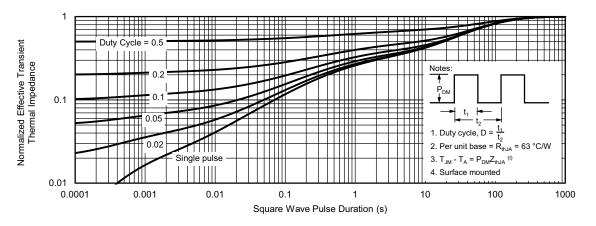
Power, Junction-to-Case

Power, Junction-to-Ambient

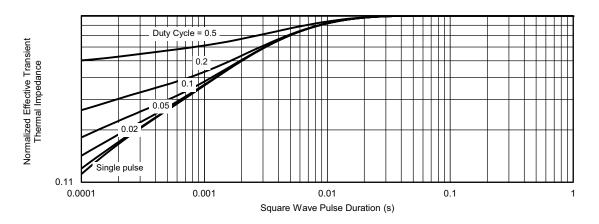
Note

a. The power dissipation P_D is based on T_J max. = 150 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit





Normalized Thermal Transient Impedance, Junction-to-Ambient



Normalized Thermal Transient Impedance, Junction-to-Case



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